PROCEEDINGS OF SPIE

Reflection, Scattering, and Diffraction from Surfaces IV

Leonard M. Hanssen
Editor

17–18 August 2014
San Diego, California, United States

Sponsored and Published by
SPIE

Volume 9205

Proceedings of SPIE 0277-786X, V. 9205

Reflection, Scattering, and Diffraction from Surfaces IV, edited by Leonard M. Hanssen,
Proc. of SPIE Vol. 9205, 920501 · © 2014 SPIE · CCC code: 0277-786X/14/$18
doi: 10.1117/12.2084706

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Author(s), "Title of Paper," in *Reflection, Scattering, and Diffraction from Surfaces IV*, edited by Leonard M. Hanssen, Proceedings of SPIE Vol. 9205 (SPIE, Bellingham, WA, 2014) Article CID Number.

ISSN: 0277-786X
ISBN: 9781628412321

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org

Printed in the United States of America.

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